


<b>Search Notes</b>  	<b>Application/Control No.</b>  10709026	<b>Applicant(s)/Patent Under Reexamination</b>  HSIAO, YUAN-KUN
	<b>Examiner</b>  Singh, Hirdepal	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	326, 362, 371, 373, 375-376	9/10/2007	HS
327	113	9/10/2007	HS
455	130, 214	9/10/2007	HS
375	315,326, 362, 371, 373, 375-376	11/20/2007	HS
369	44.13, 44.26, 44.28, 47, 275.4	11/20/2007	HS
327	3,5,7,12	11/20/2007	HS
455	130,214	11/20/2007	HS

SEARCH NOTES			
Search Notes		Date	Examiner
US-PG PUB; USPAT; USOCR; FPRS; EPO; JPO; IBM-TDB; DERWENT		9/10/2007	HS
US-PG PUB; USPAT; USOCR; FPRS; EPO; JPO; IBM-TDB; DERWENT		11/20/2007	HS
Google Search		11/20/2007	HS
IEEE Search		11/20/2007	HS
Plus search		11/20/2007	HS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
375	315	11/20/2007	HS
375	326	11/20/2007	HS
375	362	11/20/2007	HS
375	371	11/20/2007	HS
375	375	11/20/2007	HS
375	376	11/20/2007	HS
327	3	11/20/2007	HS
327	5	11/20/2007	HS
327	7	11/20/2007	